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Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Active
Core Processor	PowerPC e500
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	533MHz
Co-Processors/DSP	Communications; CPM, Security; SEC
RAM Controllers	DDR, SDRAM
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (2)
SATA	-
USB	USB 2.0 (1)
Voltage - I/O	2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	Cryptography, Random Number Generator
Package / Case	783-BBGA, FCBGA
Supplier Device Package	783-FCPBGA (29x29)
Purchase URL	https://www.e-xfl.com/pro/item?MUrl=&PartUrl=mpc8555epxajd

1 Overview

The following section provides a high-level overview of the MPC8555E features. Figure 1 shows the major functional units within the MPC8555E.

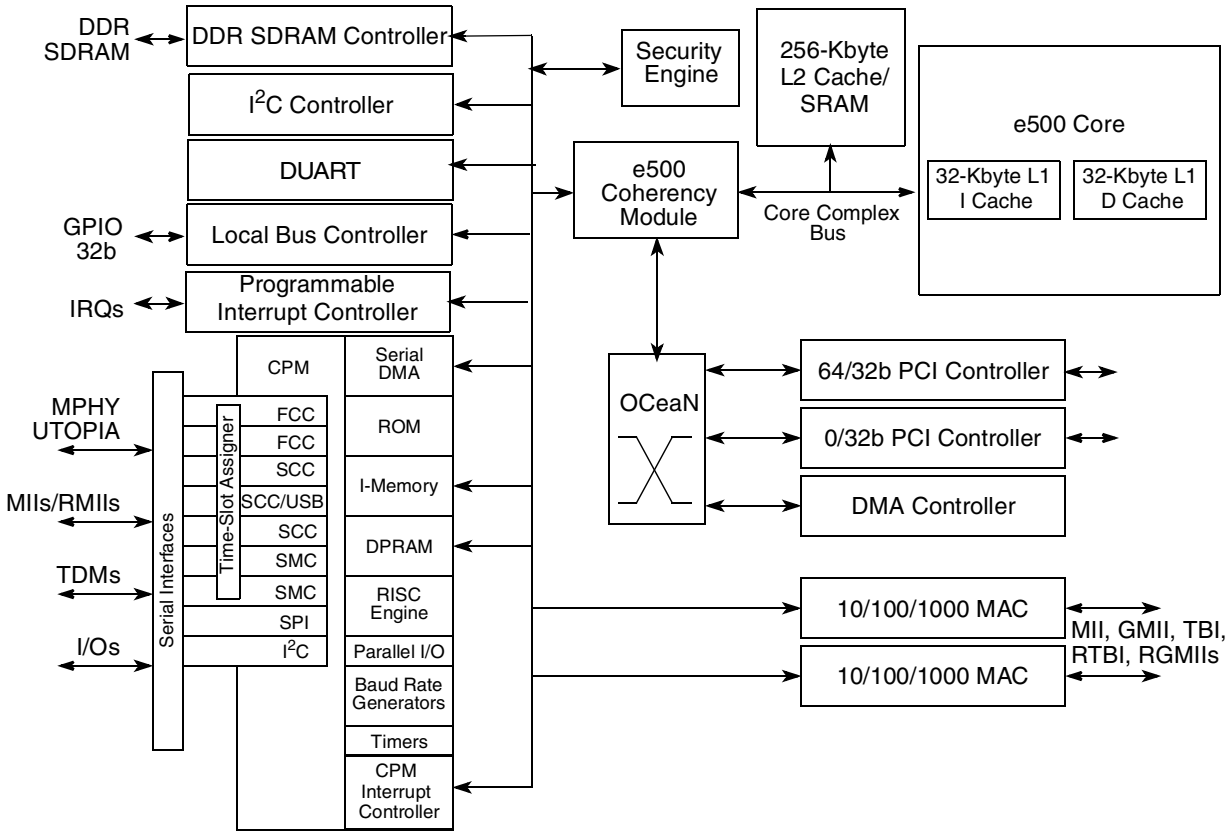


Figure 1. MPC8555E Block Diagram

1.1 Key Features

The following lists an overview of the MPC8555E feature set.

- Embedded e500 Book E-compatible core
  - High-performance, 32-bit Book E-enhanced core that implements the PowerPC architecture
  - Dual-issue superscalar, 7-stage pipeline design
  - 32-Kbyte L1 instruction cache and 32-Kbyte L1 data cache with parity protection
  - Lockable L1 caches—entire cache or on a per-line basis
  - Separate locking for instructions and data
  - Single-precision floating-point operations
  - Memory management unit especially designed for embedded applications
  - Enhanced hardware and software debug support
  - Dynamic power management
  - Performance monitor facility

- Security Engine is optimized to handle all the algorithms associated with IPSec, SSL/TLS, SRTP, IEEE Std 802.11i™, iSCSI, and IKE processing. The Security Engine contains 4 Crypto-channels, a Controller, and a set of crypto Execution Units (EUs). The Execution Units are:
  - Public Key Execution Unit (PKEU) supporting the following:
    - RSA and Diffie-Hellman
    - Programmable field size up to 2048-bits
    - Elliptic curve cryptography
    - F2m and F(p) modes
    - Programmable field size up to 511-bits
  - Data Encryption Standard Execution Unit (DEU)
    - DES, 3DES
    - Two key (K1, K2) or Three Key (K1, K2, K3)
    - ECB and CBC modes for both DES and 3DES
  - Advanced Encryption Standard Unit (AESU)
    - Implements the Rinjdael symmetric key cipher
    - Key lengths of 128, 192, and 256 bits.Two key
    - ECB, CBC, CCM, and Counter modes
  - ARC Four execution unit (AFEU)
    - Implements a stream cipher compatible with the RC4 algorithm
    - 40- to 128-bit programmable key
  - Message Digest Execution Unit (MDEU)
    - SHA with 160-bit or 256-bit message digest
    - MD5 with 128-bit message digest
    - HMAC with either algorithm
  - Random Number Generator (RNG)
  - 4 Crypto-channels, each supporting multi-command descriptor chains
    - Static and/or dynamic assignment of crypto-execution units via an integrated controller
    - Buffer size of 256 Bytes for each execution unit, with flow control for large data sizes
- High-performance RISC CPM operating at up to 333 MHz
  - CPM software compatibility with previous PowerQUICC families
  - One instruction per clock
  - Executes code from internal ROM or instruction RAM
  - 32-bit RISC architecture
  - Tuned for communication environments: instruction set supports CRC computation and bit manipulation.
  - Internal timer
  - Interfaces with the embedded e500 core processor through a 32-Kbyte dual-port RAM and virtual DMA channels for each peripheral controller
  - Handles serial protocols and virtual DMA

6 DDR SDRAM

This section describes the DC and AC electrical specifications for the DDR SDRAM interface of the MPC8555E.

6.1 DDR SDRAM DC Electrical Characteristics

Table 11 provides the recommended operating conditions for the DDR SDRAM component(s) of the MPC8555E.

Table 11. DDR SDRAM DC Electrical Characteristics

Parameter/Condition	Symbol	Min	Max	Unit	Notes
I/O supply voltage	GV_{DD}	2.375	2.625	V	1
I/O reference voltage	MV_{REF}	$0.49 \times GV_{DD}$	$0.51 \times GV_{DD}$	V	2
I/O termination voltage	V_{TT}	$MV_{REF} - 0.04$	$MV_{REF} + 0.04$	V	3
Input high voltage	V_{IH}	$MV_{REF} + 0.18$	$GV_{DD} + 0.3$	V	—
Input low voltage	V_{IL}	–0.3	$MV_{REF} - 0.18$	V	—
Output leakage current	I_{OZ}	–10	10	µA	4
Output high current (V_{OUT} = 1.95 V)	I_{OH}	–15.2	—	mA	—
Output low current (V_{OUT} = 0.35 V)	I_{OL}	15.2	—	mA	—
MV_{REF} input leakage current	I_{VREF}	—	5	µA	—

Notes:
1. GV_{DD} is expected to be within 50 mV of the DRAM GV_{DD} at all times.
2. MV_{REF} is expected to be equal to $0.5 \times GV_{DD}$, and to track GV_{DD} DC variations as measured at the receiver. Peak-to-peak noise on MV_{REF} may not exceed ±2% of the DC value.
3. V_{TT} is not applied directly to the device. It is the supply to which far end signal termination is made and is expected to be equal to MV_{REF}. This rail should track variations in the DC level of MV_{REF}.
4. Output leakage is measured with all outputs disabled, $0 V \le V_{OUT} \le GV_{DD}$.

Table 12 provides the DDR capacitance.

Table 12. DDR SDRAM Capacitance

Parameter/Condition	Symbol	Min	Max	Unit	Notes
Input/output capacitance: DQ, DQS, MSYNC_IN	C_{IO}	6	8	pF	1
Delta input/output capacitance: DQ, DQS	C_{DIO}	—	0.5	pF	1

Note:
1. This parameter is sampled. GV_{DD} = 2.5 V ± 0.125 V, f = 1 MHz, T_A = 25°C, $V_{OUT} = GV_{DD}/2$, V_{OUT} (peak to peak) = 0.2 V.

6.2 DDR SDRAM AC Electrical Characteristics

This section provides the AC electrical characteristics for the DDR SDRAM interface.

6.2.1 DDR SDRAM Input AC Timing Specifications

Table 13 provides the input AC timing specifications for the DDR SDRAM interface.

Table 13. DDR SDRAM Input AC Timing Specifications

At recommended operating conditions with GV_{DD} of 2.5 V ± 5%.

Parameter	Symbol	Min	Max	Unit	Notes
AC input low voltage	V_{IL}	—	MV_{REF} – 0.31	V	—
AC input high voltage	V_{IH}	MV_{REF} + 0.31	GV_{DD} + 0.3	V	—
MDQS—MDQ/MECC input skew per byte For DDR = 333 MHz For DDR ≤ 266 MHz	t_{DISKEW}	—	 750 1125	ps	1

Note:

1. Maximum possible skew between a data strobe (MDQS[n]) and any corresponding bit of data (MDQ[8n + {0...7}] if 0 <= n <= 7) or ECC (MECC[{0...7}] if n = 8).

6.2.2 DDR SDRAM Output AC Timing Specifications

Table 14 and Table 15 provide the output AC timing specifications and measurement conditions for the DDR SDRAM interface.

Table 14. DDR SDRAM Output AC Timing Specifications for Source Synchronous Mode

At recommended operating conditions with GV_{DD} of 2.5 V ± 5%.

Parameter	Symbol [1]	Min	Max	Unit	Notes
MCK[n] cycle time, (MCK[n]/$\overline{\text{MCK}}$[n] crossing)	t_{MCK}	6	10	ns	2
Skew between any MCK to ADDR/CMD 333 MHz 266 MHz 200 MHz	t_{AOSKEW}	 –1000 –1100 –1200	 200 300 400	ps	3
ADDR/CMD output setup with respect to MCK 333 MHz 266 MHz 200 MHz	t_{DDKHAS}	 2.8 3.45 4.6	—	ns	4
ADDR/CMD output hold with respect to MCK 333 MHz 266 MHz 200 MHz	t_{DDKHAX}	 2.0 2.65 3.8	—	ns	4
$\overline{\text{MCS}}$(n) output setup with respect to MCK 333 MHz 266 MHz 200 MHz	t_{DDKHCS}	 2.8 3.45 4.6	—	ns	4

8.2.2.1 GMII Receive AC Timing Specifications

Table 21 provides the GMII receive AC timing specifications.

Table 21. GMII Receive AC Timing Specifications

At recommended operating conditions with LV_{DD} of 3.3 V ± 5%.

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit
RX_CLK clock period	t_{GRX}	—	8.0	—	ns
RX_CLK duty cycle	t_{GRXH}/t_{GRX}	40	—	60	%
RXD[7:0], RX_DV, RX_ER setup time to RX_CLK	t_{GRDVKH}	2.0	—	—	ns
RXD[7:0], RX_DV, RX_ER hold time to RX_CLK	t_{GRDXKH}	0.5	—	—	ns
RX_CLK clock rise and fall time	t_{GRXR}, t_{GRXF} [2,3]	—	—	1.0	ns

Note:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{GRDVKH} symbolizes GMII receive timing (GR) with respect to the time data input signals (D) reaching the valid state (V) relative to the t_{RX} clock reference (K) going to the high state (H) or setup time. Also, t_{GRDXKL} symbolizes GMII receive timing (GR) with respect to the time data input signals (D) went invalid (X) relative to the t_{GRX} clock reference (K) going to the low (L) state or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{GRX} represents the GMII (G) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. Signal timings are measured at 0.7 V and 1.9 V voltage levels.
3. Guaranteed by design.

Figure 8 provides the AC test load for TSEC.

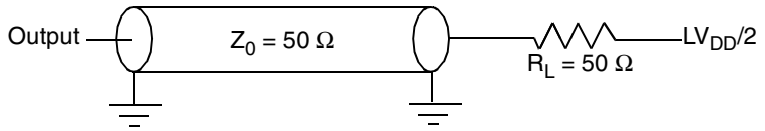


Figure 8. TSEC AC Test Load

Figure 9 shows the GMII receive AC timing diagram.

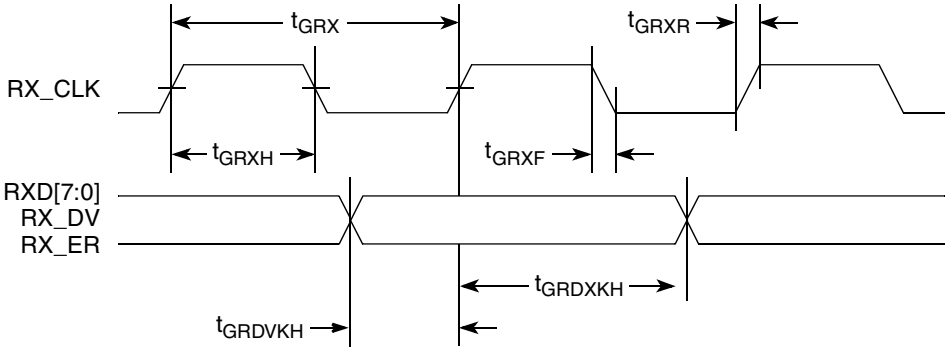


Figure 9. GMII Receive AC Timing Diagram

8.2.5 RGMII and RTBI AC Timing Specifications

Table 26 presents the RGMII and RTBI AC timing specifications.

Table 26. RGMII and RTBI AC Timing Specifications

At recommended operating conditions with LV_{DD} of 2.5 V ± 5%.

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit
Data to clock output skew (at transmitter)	t_{SKRGT}[5]	–500	0	500	ps
Data to clock input skew (at receiver) [2]	t_{SKRGT}	1.0	—	2.8	ns
Clock cycle duration [3]	t_{RGT}[6]	7.2	8.0	8.8	ns
Duty cycle for 1000Base-T [4]	t_{RGTH}/t_{RGT}[6]	45	50	55	%
Duty cycle for 10BASE-T and 100BASE-TX [3]	t_{RGTH}/t_{RGT}[6]	40	50	60	%
Rise and fall times	t_{RGTR}[6,7], t_{RGTF}[6,7]	—	—	0.75	ns

Notes:

1. Note that, in general, the clock reference symbol representation for this section is based on the symbols RGT to represent RGMII and RTBI timing. For example, the subscript of t_{RGT} represents the TBI (T) receive (RX) clock. Note also that the notation for rise (R) and fall (F) times follows the clock symbol that is being represented. For symbols representing skews, the subscript is skew (SK) followed by the clock that is being skewed (RGT).
2. The RGMII specification requires that PC board designer add 1.5 ns or greater in trace delay to the RX_CLK in order to meet this specification. However, as stated above, this device functions with only 1.0 ns of delay.
3. For 10 and 100 Mbps, t_{RGT} scales to 400 ns ± 40 ns and 40 ns ± 4 ns, respectively.
4. Duty cycle may be stretched/shrunk during speed changes or while transitioning to a received packet's clock domains as long as the minimum duty cycle is not violated and stretching occurs for no more than three t_{RGT} of the lowest speed transitioned between.
5. Guaranteed by characterization.
6. Guaranteed by design.
7. Signal timings are measured at 0.5 and 2.0 V voltage levels.

Figure 14 shows the RBMII and RTBI AC timing and multiplexing diagrams.

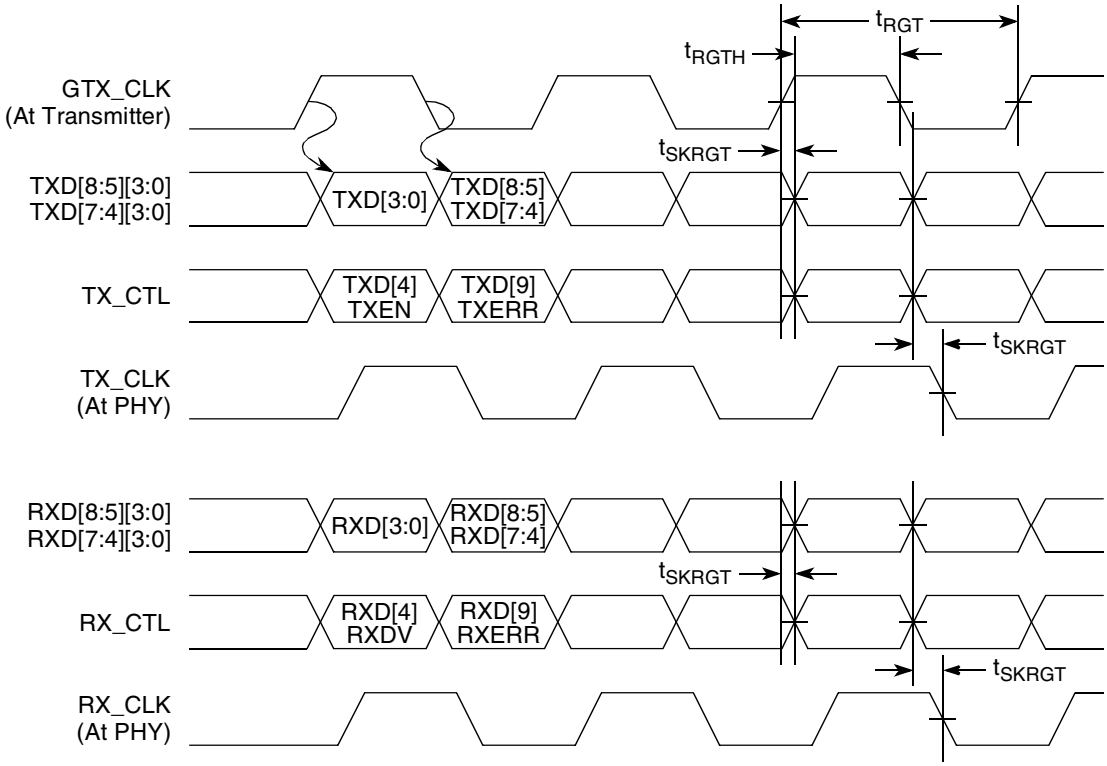


Figure 14. RGMII and RTBI AC Timing and Multiplexing Diagrams

8.3 Ethernet Management Interface Electrical Characteristics

The electrical characteristics specified here apply to MII management interface signals MDIO (management data input/output) and MDC (management data clock). The electrical characteristics for GMII, RGMII, TBI and RTBI are specified in Section 8.1, "Three-Speed Ethernet Controller (TSEC) (10/100/1000 Mbps)—GMII/MII/TBI/RGMII/RTBI Electrical Characteristics."

8.3.1 MII Management DC Electrical Characteristics

The MDC and MDIO are defined to operate at a supply voltage of 3.3 V. The DC electrical characteristics for MDIO and MDC are provided in Table 27.

Table 27. MII Management DC Electrical Characteristics

Parameter	Symbol	Conditions		Min	Max	Unit
Supply voltage (3.3 V)	OV_{DD}	—		3.13	3.47	V
Output high voltage	V_{OH}	I_{OH} = –1.0 mA	LV_{DD} = Min	2.10	LV_{DD} + 0.3	V
Output low voltage	V_{OL}	I_{OL} = 1.0 mA	LV_{DD} = Min	GND	0.50	V
Input high voltage	V_{IH}	—		1.70	—	V
Input low voltage	V_{IL}	—		—	0.90	V

Figure 17 to Figure 22 show the local bus signals.

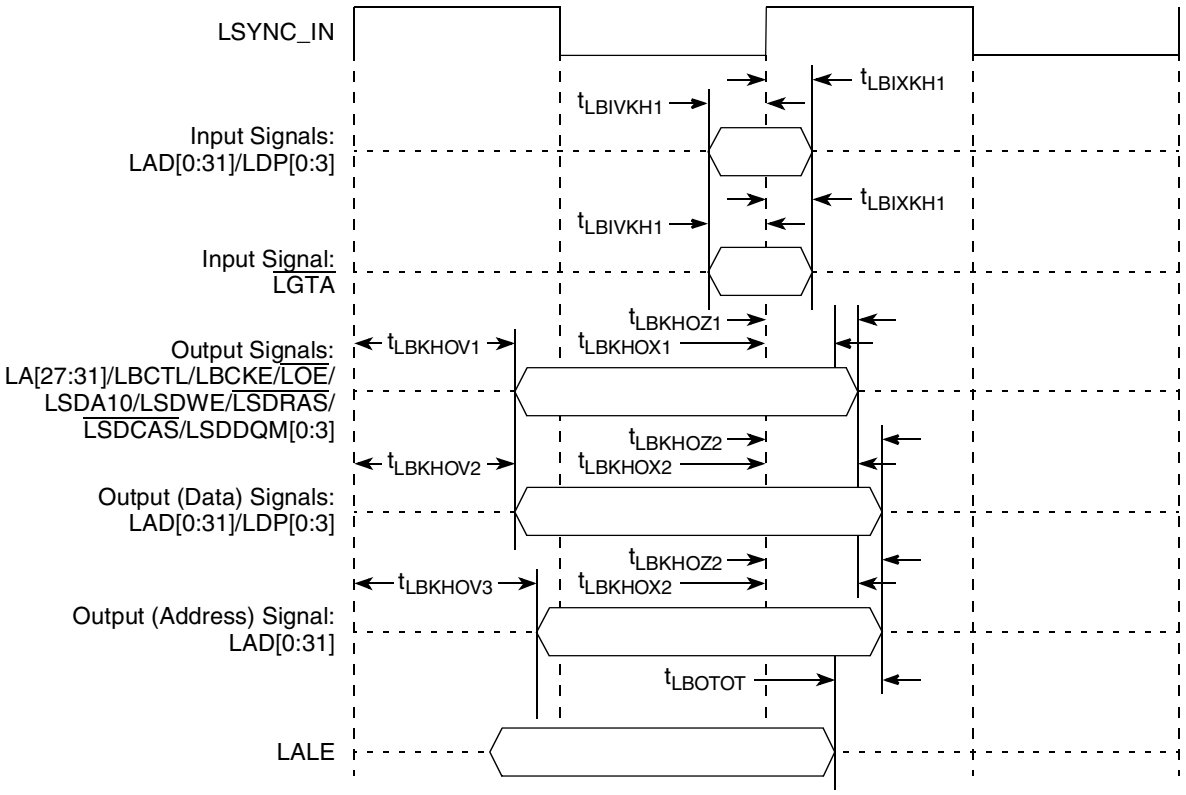


Figure 17. Local Bus Signals, Nonspecial Signals Only (DLL Enabled)

10 CPM

This section describes the DC and AC electrical specifications for the CPM of the MPC8555E.

10.1 CPM DC Electrical Characteristics

Table 32 provides the DC electrical characteristics for the CPM.

Table 32. CPM DC Electrical Characteristics

Characteristic	Symbol	Condition	Min	Max	Unit	Notes
Input high voltage	V_{IH}		2.0	3.465	V	1
Input low voltage	V_{IL}		GND	0.8	V	1, 2
Output high voltage	V_{OH}	I_{OH} = –8.0 mA	2.4	—	V	1
Output low voltage	V_{OL}	I_{OL} = 8.0 mA	—	0.5	V	1
Output high voltage	V_{OH}	I_{OH} = –2.0 mA	2.4	—	V	1
Output low voltage	V_{OL}	I_{OL} = 3.2 mA	—	0.4	V	1

Note:
1. This specification applies to the following pins: PA[0–31], PB[4–31], PC[0–31], and PD[4–31].
2. V_{IL}(max) for the IIC interface is 0.8 V rather than the 1.5 V specified in the IIC standard

10.2 CPM AC Timing Specifications

Table 33 and Table 34 provide the CPM input and output AC timing specifications, respectively.

NOTE: Rise/Fall Time on CPM Input Pins

It is recommended that the rise/fall time on CPM input pins should not exceed 5 ns. This should be enforced especially on clock signals. Rise time refers to signal transitions from 10% to 90% of VCC; fall time refers to transitions from 90% to 10% of VCC.

Table 33. CPM Input AC Timing Specifications [1]

Characteristic	Symbol [2]	Min[3]	Unit
FCC inputs—internal clock (NMSI) input setup time	t_{FIIVKH}	6	ns
FCC inputs—internal clock (NMSI) hold time	t_{FIIXKH}	0	ns
FCC inputs—external clock (NMSI) input setup time	t_{FEIVKH}	2.5	ns
FCC inputs—external clock (NMSI) hold time	t_{FEIXKH}b	2	ns
SCC/SMC/SPI inputs—internal clock (NMSI) input setup time	t_{NIIVKH}	6	ns
SCC/SMC/SPI inputs—internal clock (NMSI) input hold time	t_{NIIXKH}	0	ns
SCC/SMC/SPI inputs—external clock (NMSI) input setup time	t_{NEIVKH}	4	ns
SCC/SMC/SPI inputs—external clock (NMSI) input hold time	t_{NEIXKH}	2	ns
TDM inputs/SI—input setup time	t_{TDIVKH}	4	ns

Table 33. CPM Input AC Timing Specifications [1] (continued)

Characteristic	Symbol [2]	Min[3]	Unit
TDM inputs/SI—hold time	t_{TDIXKH}	3	ns
PIO inputs—input setup time	t_{PIIVKH}	8	ns
PIO inputs—input hold time	t_{PIIXKH}	1	ns
COL width high (FCC)	t_{FCCH}	1.5	CLK

Notes:
1. Input specifications are measured from the 50% level of the signal to the 50% level of the rising edge of CLKIN. Timings are measured at the pin.
2. The symbols used for timing specifications herein follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{FIIVKH} symbolizes the FCC inputs internal timing (FI) with respect to the time the input signals (I) reaching the valid state (V) relative to the reference clock t_{FCC} (K) going to the high (H) state or setup time. And t_{TDIXKH} symbolizes the TDM timing (TD) with respect to the time the input signals (I) reach the invalid state (X) relative to the reference clock t_{FCC} (K) going to the high (H) state or hold time.
3. PIO and TIMER inputs and outputs are asynchronous to SYSCLK or any other externally visible clock. PIO/TIMER inputs are internally synchronized to the CPM internal clock. PIO/TIMER outputs should be treated as asynchronous.

Table 34. CPM Output AC Timing Specifications [1]

Characteristic	Symbol [2]	Min	Max	Unit
FCC outputs—internal clock (NMSI) delay	t_{FIKHOX}	1	5.5	ns
FCC outputs—external clock (NMSI) delay	t_{FEKHOX}	2	8	ns
SCC/SMC/SPI outputs—internal clock (NMSI) delay	t_{NIKHOX}	0.5	10	ns
SCC/SMC/SPI outputs—external clock (NMSI) delay	t_{NEKHOX}	2	8	ns
TDM outputs/SI delay	t_{TDKHOX}	2.5	11	ns
PIO outputs delay	t_{PIKHOX}	1	11	ns

Notes:
1. Output specifications are measured from the 50% level of the rising edge of CLKIN to the 50% level of the signal. Timings are measured at the pin.
2. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{FIKHOX} symbolizes the FCC inputs internal timing (FI) for the time t_{FCC} memory clock reference (K) goes from the high state (H) until outputs (O) are invalid (X).

Figure 23 provides the AC test load for the CPM.

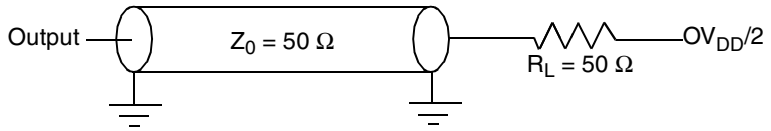
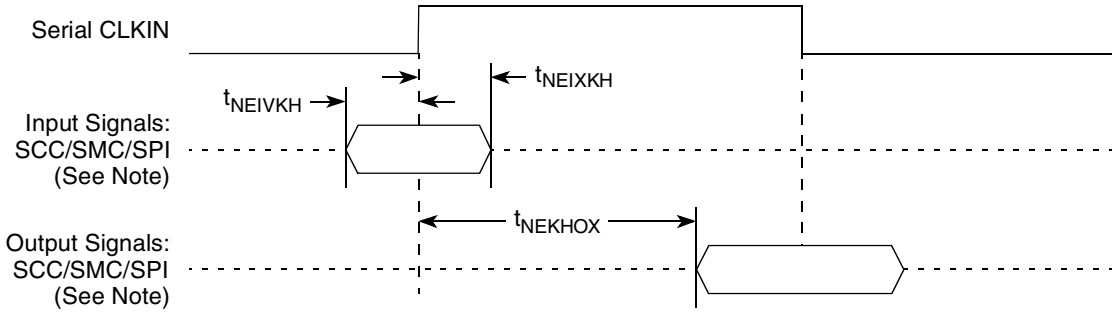


Figure 23. CPM AC Test Load

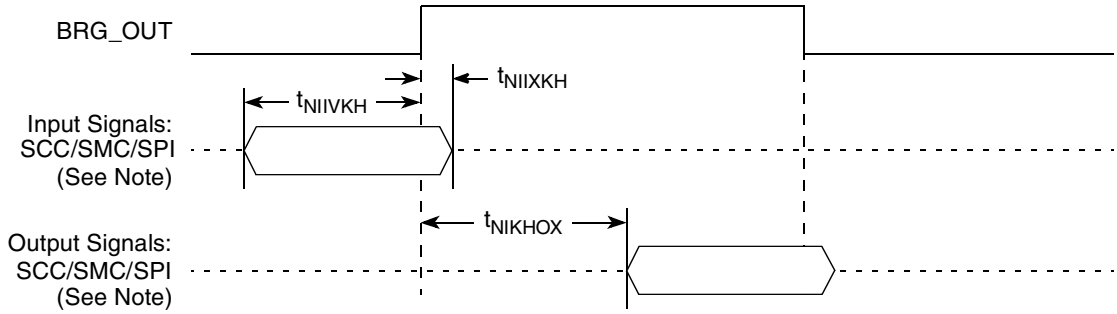
Figure 27 shows the SCC/SMC/SPI external clock.



Note: The clock edge is selectable on SCC and SPI.

Figure 27. SCC/SMC/SPI AC Timing External Clock Diagram

Figure 28 shows the SCC/SMC/SPI internal clock.



Note: The clock edge is selectable on SCC and SPI.

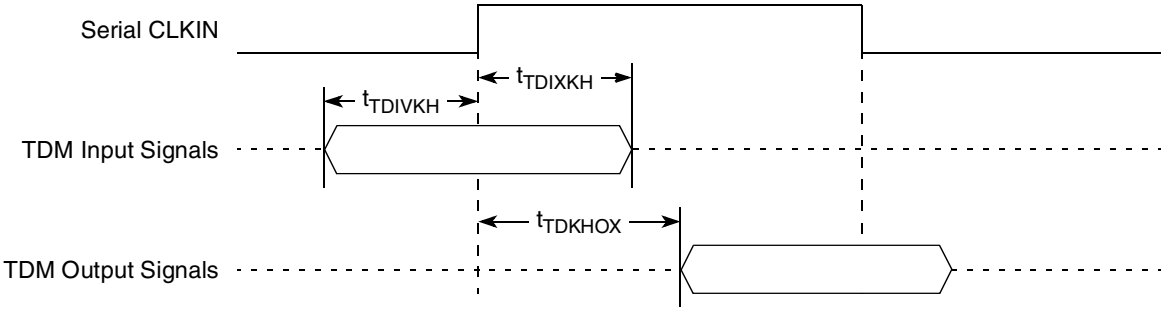
Figure 28. SCC/SMC/SPI AC Timing Internal Clock Diagram

NOTE

[1] SPI AC timings are internal mode when it is master because SPICLK is an output, and external mode when it is slave.

[2] SPI AC timings refer always to SPICLK.

Figure 29 shows TDM input and output signals.



Note: There are 4 possible TDM timing conditions:
1. Input sampled on the rising edge and output driven on the rising edge (shown).
2. Input sampled on the rising edge and output driven on the falling edge.
3. Input sampled on the falling edge and output driven on the falling edge.
4. Input sampled on the falling edge and output driven on the rising edge.

Figure 29. TDM Signal AC Timing Diagram

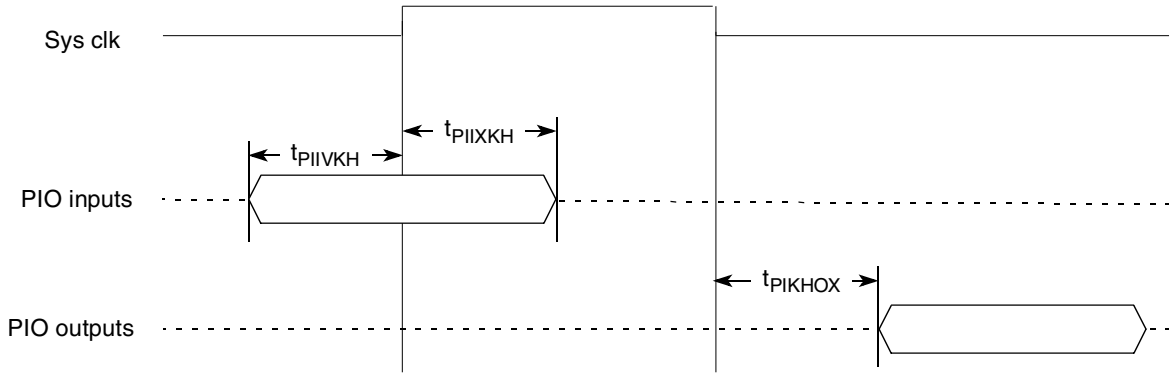


Figure 30. PIO Signal Diagram

10.3 CPM I2C AC Specification

Table 35. I2C Timing

Characteristic	Expression	All Frequencies		Unit
		Min	Max	
SCL clock frequency (slave)	f_{SCL}	0	F_{MAX} (1)	Hz
SCL clock frequency (master)	f_{SCL}	BRGCLK/16512	BRGCLK/48	Hz
Bus free time between transmissions	t_{SDHDL}	1/(2.2 * f_{SCL})	-	s
Low period of SCL	t_{SCLCH}	1/(2.2 * f_{SCL})	-	s
High period of SCL	t_{SCHCL}	1/(2.2 * f_{SCL})	-	s
Start condition setup time[2]	t_{SCHDL}	2/(divider * f_{SCL})	- (2)	s
Start condition hold time[2]	t_{SDLCL}	3/(divider * f_{SCL})	-	s
Data hold time [2]	t_{SCLDX}	2/(divider * f_{SCL})	-	s
Data setup time[2]	t_{SDVCH}	3/(divider * f_{SCL})	-	s
SDA/SCL rise time	t_{SRISE}	-	1/(10 * f_{SCL})	s

Table 43. MPC8555E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
PCI2_GNT[1:4]	AD18, AE18, AE19, AD19	O	OV_{DD}	5, 9
PCI2_IDSEL	AC22	I	OV_{DD}	—
PCI2_IRDY	AD20	I/O	OV_{DD}	2
PCI2_PERR	AC20	I/O	OV_{DD}	2
PCI2_REQ[0]	AD21	I/O	OV_{DD}	—
PCI2_REQ[1:4]	AE21, AD22, AE22, AC23	I	OV_{DD}	—
PCI2_SERR	AE20	I/O	OV_{DD}	2,4
PCI2_STOP	AC21	I/O	OV_{DD}	2
PCI2_TRDY	AC19	I/O	OV_{DD}	2
DDR SDRAM Memory Interface				
MDQ[0:63]	M26, L27, L22, K24, M24, M23, K27, K26, K22, J28, F26, E27, J26, J23, H26, G26, C26, E25, C24, E23, D26, C25, A24, D23, B23, F22, J21, G21, G22, D22, H21, E21, N18, J18, D18, L17, M18, L18, C18, A18, K17, K16, C16, B16, G17, L16, A16, L15, G15, E15, C14, K13, C15, D15, E14, D14, D13, E13, D12, A11, F13, H13, A13, B12	I/O	GV_{DD}	—
MECC[0:7]	N20, M20, L19, E19, C21, A21, G19, A19	I/O	GV_{DD}	—
MDM[0:8]	L24, H28, F24, L21, E18, E16, G14, B13, M19	O	GV_{DD}	—
MDQS[0:8]	L26, J25, D25, A22, H18, F16, F14, C13, C20	I/O	GV_{DD}	—
MBA[0:1]	B18, B19	O	GV_{DD}	—
MA[0:14]	N19, B21, F21, K21, M21, C23, A23, B24, H23, G24, K19, B25, D27, J14, J13	O	GV_{DD}	—
MWE	D17	O	GV_{DD}	—
MRAS	F17	O	GV_{DD}	—
MCAS	J16	O	GV_{DD}	—
MCS[0:3]	H16, G16, J15, H15	O	GV_{DD}	—
MCKE[0:1]	E26, E28	O	GV_{DD}	11
MCK[0:5]	J20, H25, A15, D20, F28, K14	O	GV_{DD}	—
MCK[0:5]	F20, G27, B15, E20, F27, L14	O	GV_{DD}	—
MSYNC_IN	M28	I	GV_{DD}	22
MSYNC_OUT	N28	O	GV_{DD}	22
Local Bus Controller Interface				
LA[27]	U18	O	OV_{DD}	5, 9

Table 43. MPC8555E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
TSEC2_CRS	D9	I	LV_{DD}	—
TSEC2_COL	F8	I	LV_{DD}	—
TSEC2_RXD[7:0]	F9, E9, C9, B9, A9, H9, G10, F10	I	LV_{DD}	—
TSEC2_RX_DV	H8	I	LV_{DD}	—
TSEC2_RX_ER	A8	I	LV_{DD}	—
TSEC2_RX_CLK	E10	I	LV_{DD}	—
DUART				
$\overline{\text{UART\_CTS}}$[0,1]	Y2, Y3	I	OV_{DD}	—
$\overline{\text{UART\_RTS}}$[0,1]	Y1, AD1	O	OV_{DD}	—
UART_SIN[0,1]	P11, AD5	I	OV_{DD}	—
UART_SOUT[0,1]	N6, AD2	O	OV_{DD}	—
I^2C interface				
IIC_SDA	AH22	I/O	OV_{DD}	4, 19
IIC_SCL	AH23	I/O	OV_{DD}	4, 19
System Control				
$\overline{\text{HRESET}}$	AH16	I	OV_{DD}	—
$\overline{\text{HRESET\_REQ}}$	AG20	O	OV_{DD}	18
$\overline{\text{SRESET}}$	AF20	I	OV_{DD}	—
$\overline{\text{CKSTP\_IN}}$	M11	I	OV_{DD}	—
$\overline{\text{CKSTP\_OUT}}$	G1	O	OV_{DD}	2, 4
Debug				
TRIG_IN	N12	I	OV_{DD}	—
TRIG_OUT/READY	G2	O	OV_{DD}	6, 9, 18
MSRCID[0:1]	J9, G3	O	OV_{DD}	5, 6, 9
MSRCID[2:3]	F3, F5	O	OV_{DD}	6
MSRCID4	F2	O	OV_{DD}	6
MDVAL	F4	O	OV_{DD}	6
Clock				
SYSCLK	AH21	I	OV_{DD}	—
RTC	AB23	I	OV_{DD}	—
CLK_OUT	AF22	O	OV_{DD}	—

Table 43. MPC8555E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
GND	A12, A17, B3, B14, B20, B26, B27, C2, C4, C11,C17, C19, C22, C27, D8, E3, E12, E24, F11, F18, F23, G9, G12, G25, H4, H12, H14, H17, H20, H22, H27, J19, J24, K5, K9, K18, K23, K28, L6, L20, L25, M4, M12, M14, M16, M22, M27, N2, N13, N15, N17, P12, P14, P16, P23, R13, R15, R17, R20, R26, T3, T8, T10, T12, T14, T16, U6, U13, U15, U16, U17, U21, V7, V10, V26, W5, W18, W23, Y8, Y16, AA6, AA13, AB4, AB11, AB19, AC6, AC9, AD3, AD8, AD17, AF2, AF4, AF10, AF13, AF15, AF27, AG3, AG7	—	—	—
GV_{DD}	A14, A20, A25, A26, A27, A28, B17, B22, B28, C12, C28, D16, D19, D21, D24, D28, E17, E22, F12, F15, F19, F25, G13, G18, G20, G23, G28, H19, H24, J12, J17, J22, J27, K15, K20, K25, L13, L23, L28, M25, N21	Power for DDR DRAM I/O Voltage (2.5 V)	GV_{DD}	—
LV_{DD}	A4, C5, E7, H10	Reference Voltage; Three-Speed Ethernet I/O (2.5 V, 3.3 V)	LV_{DD}	—
MV_{REF}	N27	Reference Voltage Signal; DDR	MV_{REF}	—
No Connects	AA24, AA25, AA3, AA4, AA7 AA8, AB24, AB25, AC24, AC25, AD23, AD24, AD25, AE23, AE24, AE25, AE26, AE27, AF24, AF25, H1, H2, J1, J2, J3, J4, J5, J6, M1, N1, N10, N11, N4, N5, N7, N8, N9, P10, P8, P9, R10, R11, T24, T25, U24, U25, V24, V25, W24, W25, W9, Y24, Y25, Y5, Y6, Y9, AH26, AH28, AG28, AH1, AG1, AH2, B1, B2, A2, A3	—	—	16
OV_{DD}	D1, E4, H3, K4, K10, L7, M5, N3, P22, R19, R25, T2, T7, U5, U20, U26, V8, W4, W13, W19, W21, Y7, Y23, AA5, AA12, AA16, AA20, AB7, AB9, AB26, AC5, AC11, AC17, AD4, AE1, AE8, AE10, AE15, AF7, AF12, AG27, AH4	PCI, 10/100 Ethernet, and other Standard (3.3 V)	OV_{DD}	—
RESERVED	C1, T11, U11, AF1	—	—	15
SENSEVDD	L12	Power for Core (1.2 V)	V_{DD}	13
SENSEVSS	K12	—	—	13
V_{DD}	M13, M15, M17, N14, N16, P13, P15, P17, R12, R14, R16, T13, T15, T17, U12, U14	Power for Core (1.2 V)	V_{DD}	—
CPM				
PA[8:31]	J7, J8, K8, K7, K6, K3, K2, K1, L1, L2, L3, L4, L5, L8, L9, L10, L11, M10, M9, M8, M7, M6, M3, M2	I/0	OV_{DD}	—

Table 43. MPC8555E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
PB[18:31]	P7, P6, P5, P4, P3, P2, P1, R1, R2, R3, R4, R5, R6, R7	I/O	OV_{DD}	—
PC[0, 1, 4–29]	R8, R9, T9, T6, T5, T4, T1, U1, U2, U3, U4, U7, U8, U9, U10, V9, V6, V5, V4, V3, V2, V1, W1, W2, W3, W6, W7, W8	I/O	OV_{DD}	—
PD[7, 14–25, 29–31]	Y4, AA2, AA1, AB1, AB2, AB3, AB5, AB6, AC7, AC4, AC3, AC2, AC1, AD6, AE3, AE2	I/O	OV_{DD}	—

Notes:
1. All multiplexed signals are listed only once and do not re-occur. For example, $\overline{\text{LCS5}}$/$\overline{\text{DMA\_REQ2}}$ is listed only once in the Local Bus Controller Interface section, and is not mentioned in the DMA section even though the pin also functions as $\overline{\text{DMA\_REQ2}}$.
2. Recommend a weak pull-up resistor (2–10 kΩ) be placed on this pin to OV_{DD}.
3. TEST_SEL0 must be pulled-high, TEST_SEL1 must be tied to ground.
4. This pin is an open drain signal.
5. This pin is a reset configuration pin. It has a weak internal pull-up P-FET which is enabled only when the MPC8555E is in the reset state. This pull-up is designed such that it can be overpowered by an external 4.7-kΩ pull-down resistor. If an external device connected to this pin might pull it down during reset, then a pull-up or active driver is needed if the signal is intended to be high during reset.
6. Treat these pins as no connects (NC) unless using debug address functionality.
7. The value of LA[28:31] during reset sets the CCB clock to SYSCLK PLL ratio. These pins require 4.7-kΩ pull-up or pull-down resistors. See Section 15.2, “Platform/System PLL Ratio.”
8. The value of LALE and LGPL2 at reset set the e500 core clock to CCB Clock PLL ratio. These pins require 4.7-kΩ pull-up or pull-down resistors. See the Section 15.3, “e500 Core PLL Ratio.”
9. Functionally, this pin is an output, but structurally it is an I/O because it either samples configuration input during reset or because it has other manufacturing test functions. This pin therefore is described as an I/O for boundary scan.
10. This pin functionally requires a pull-up resistor, but during reset it is a configuration input that controls 32- vs. 64-bit PCI operation. Therefore, it must be actively driven low during reset by reset logic if the device is to be configured to be a 64-bit PCI device. Refer to the *PCI Specification*.
11. This output is actively driven during reset rather than being three-stated during reset.
12. These JTAG pins have weak internal pull-up P-FETs that are always enabled.
13. These pins are connected to the V_{DD}/GND planes internally and may be used by the core power supply to improve tracking and regulation.
14. Internal thermally sensitive resistor.
15. No connections should be made to these pins.
16. These pins are not connected for any functional use.
17. PCI specifications recommend that a weak pull-up resistor (2–10 kΩ) be placed on the higher order pins to OV_{DD} when using 64-bit buffer mode (pins PCI_AD[63:32] and $\overline{\text{PCI2\_C\_BE}}$[7:4]).
18. If this pin is connected to a device that pulls down during reset, an external pull-up is required to that is strong enough to pull this signal to a logic 1 during reset.
19. Recommend a pull-up resistor (~1 kΩ) be placed on this pin to OV_{DD}.
20. These are test signals for factory use only and must be pulled up (100Ω to $1\text{k}\Omega$) to OV_{DD} for normal machine operation.
21. If this signal is used as both an input and an output, a weak pull-up ($\sim 10\text{k}\Omega$) is required on this pin.
22. MSYNC_IN and MSYNC_OUT should be connected together for proper operation.

16.2.2 Internal Package Conduction Resistance

For the packaging technology, shown in Table 49, the intrinsic internal conduction thermal resistance paths are as follows:

- The die junction-to-case thermal resistance
- The die junction-to-board thermal resistance

Figure 45 depicts the primary heat transfer path for a package with an attached heat sink mounted to a printed-circuit board.

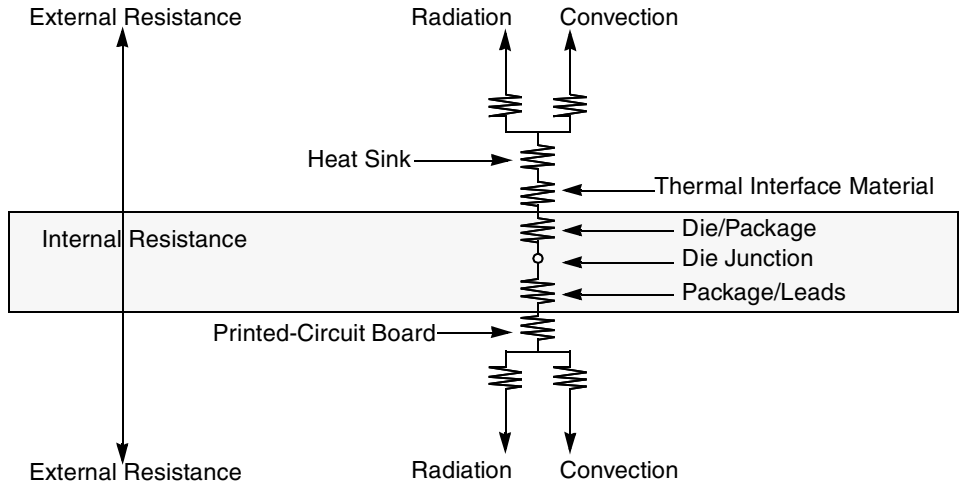


Figure 45. Package with Heat Sink Mounted to a Printed-Circuit Board

The heat sink removes most of the heat from the device. Heat generated on the active side of the chip is conducted through the silicon and through the lid, then through the heat sink attach material (or thermal interface material), and finally to the heat sink. The junction-to-case thermal resistance is low enough that the heat sink attach material and heat sink thermal resistance are the dominant terms.

16.2.3 Thermal Interface Materials

A thermal interface material is required at the package-to-heat sink interface to minimize the thermal contact resistance. For those applications where the heat sink is attached by spring clip mechanism, Figure 46 shows the thermal performance of three thin-sheet thermal-interface materials (silicone, graphite/oil, floroether oil), a bare joint, and a joint with thermal grease as a function of contact pressure. As shown, the performance of these thermal interface materials improves with increasing contact pressure. The use of thermal grease significantly reduces the interface thermal resistance. The bare joint results in a thermal resistance approximately six times greater than the thermal grease joint.

Heat sinks are attached to the package by means of a spring clip to holes in the printed-circuit board (see Figure 42). Therefore, the synthetic grease offers the best thermal performance, especially at the low interface pressure.

When removing the heat sink for re-work, it is preferable to slide the heat sink off slowly until the thermal interface material loses its grip. If the support fixture around the package prevents sliding off the heat sink,

The spring mounting should be designed to apply the force only directly above the die. By localizing the force, rocking of the heat sink is minimized. One suggested mounting method attaches a plastic fence to the board to provide the structure on which the heat sink spring clips. The plastic fence also provides the opportunity to minimize the holes in the printed-circuit board and to locate them at the corners of the package. Figure 48 and provide exploded views of the plastic fence, heat sink, and spring clip.

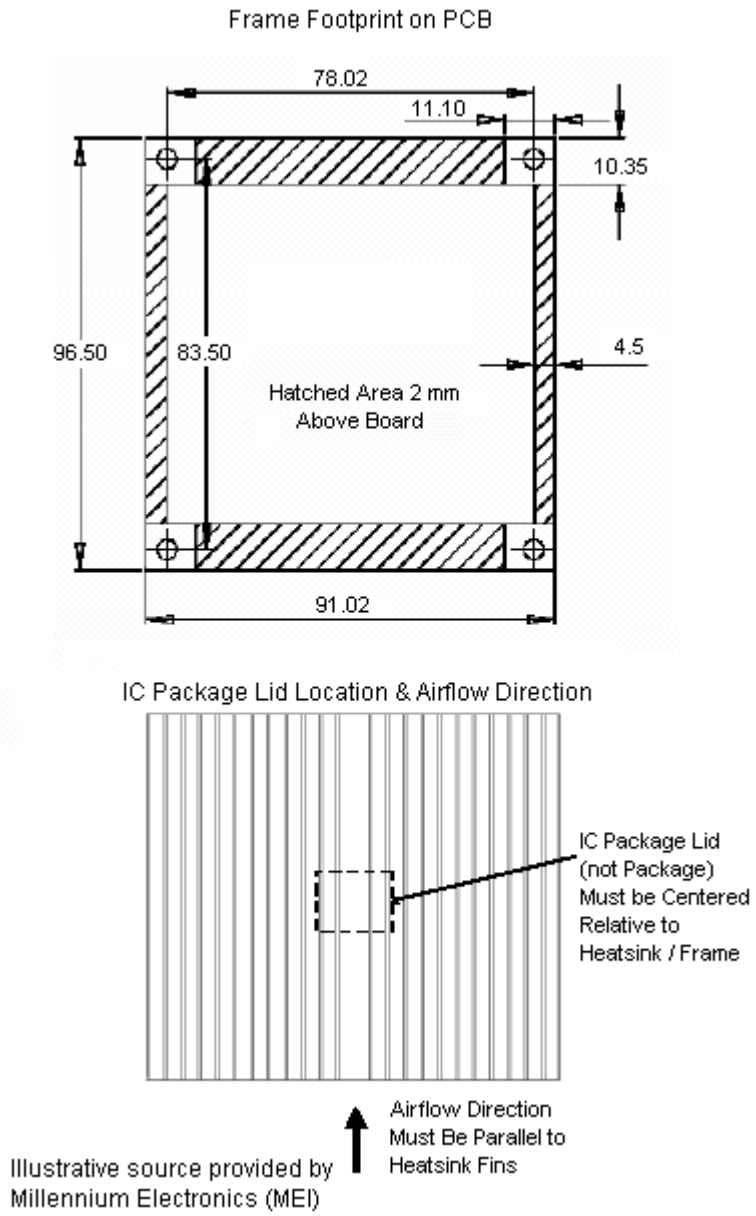


Figure 48. Exploded Views (1) of a Heat Sink Attachment using a Plastic Fence

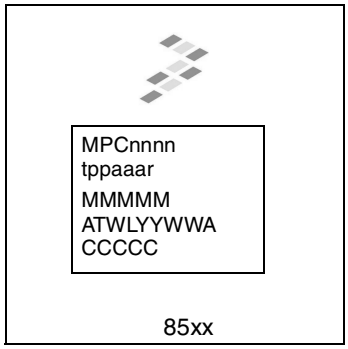
17.8.1 Termination of Unused Signals

If the JTAG interface and COP header are not used, Freescale recommends the following connections:

- $\overline{\text{TRST}}$ should be tied to $\overline{\text{HRESET}}$ through a 0 kΩ isolation resistor so that it is asserted when the system reset signal ($\overline{\text{HRESET}}$) is asserted, ensuring that the JTAG scan chain is initialized during the power-on reset flow. Freescale recommends that the COP header be designed into the system as shown in Figure 53. If this is not possible, the isolation resistor allows future access to $\overline{\text{TRST}}$ in case a JTAG interface may need to be wired onto the system in future debug situations.
- Tie TCK to OV_{DD} through a 10 kΩ resistor. This prevents TCK from changing state and reading incorrect data into the device.
- No connection is required for TDI, TMS, or TDO.

19.2 Part Marking

Parts are marked as the example shown in Figure 54.



FC-PBGA

Notes:
MMMMM is the 5-digit mask number.
ATWLYYWWA is the traceability code.
CCCCC is the country of assembly. This space is left blank if parts are assembled in the United States.

Figure 54. Part Marking for FC-PBGA Device